I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail, in an envelope addressed to. Commissioner for Patents, Washington, DC 2023 n on the date shown below.

Dated: November 20, 2002

Signature

Docket No.: 101328-0148

(PATENT)

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of: Theodore H. Fedynyshyn

Application No.: 09/512,942

Filed: February 25, 2000

For: ENCAPSULATED INORGANIC RESISTS

Group Art Unit: 1752

Examiner: J. Chu

RECEIVED

**AMENDMENT AND RESPONSE UNDER 37 CFR 1.116** 

**BOX AF** Commissioner for Patents Washington, DC 20231

Dear Sir:

Applicant thanks the Examiner for extending to Applicant's representatives the opportunity to discuss the outstanding issues in the present application during a telephonic interview on October 23, 2002. In view of this discussion, in response to the final Office Action mailed from the United States Patent and Trademark Office on June 20, 2002, Applicant provides the attached Declaration under 37 C.F.R. 1.132, and the following remarks to establish that the invention distinguishes patentably over the cited reference. Accordingly, reconsideration and allowance of the application are respectfully requested.

## **REMARKS**

The present invention provides photosensitive resist materials, useful in lithography, that include colloidal particles that significantly increase the plasma etch sensitivity of the photoresist materials. More particularly, the invention provides positive photoresist compositions that include encapsulated inorganic core particles, and that are base soluble upon activation by radiation.